

# Determining Clamping Voltage Levels for a Range of Pulse Currents

Clamping voltage ( $V_C$ ) is specified only at the maximum limit on most silicon transient voltage suppressor (TVS) data sheets. Often the designer needs to determine the  $V_C$  at some intermediate level between breakdown voltage ( $V_{(BR)}$ ) and maximum  $V_C$ .

The value can be calculated with the data sheet parameters using the formula:

$$V_C = (I_p/I_{pp})(V_{C \text{ max}} - V_{(BR) \text{ max}}) + V_{(BR) \text{ max}}$$

Where:

- $I_p$  = actual test pulse current
- $I_{pp}$  = maximum rated peak pulse current
- $V_C$  = clamping voltage at  $I_p$
- $V_{C \text{ max}}$  = maximum specified clamping voltage
- $V_{(BR)}$  = upper limit of breakdown voltage

Based on previous data, a linear increase in  $V_C$  can be assumed between  $V_{(BR)}$  and  $V_{C \text{ max}}$  for this formula. The  $V_C$  versus  $I_p$  relationship for the SMCJ15A for a 1.5 kW TVS between  $V_{(BR)}$  and  $V_C$  as calculated by this method is shown in Figure 1. Results are as expected. This calculation assumes the TVS to be at the  $V_{(BR)}$  upper limit, hence it would be conservative for most of the distribution. Note that when  $I_p$  equals  $I_{pp}$ ,  $V_C$  equals  $V_{C \text{ max}}$ .

If only  $V_{(BR) \text{ min}}$  is listed on the data sheet,  $V_{(BR) \text{ max}}$  can be approximated. For "A" suffix parts, multiply  $V_{(BR) \text{ min}}$  by 1.20 and for non-suffix parts, multiply by 1.25 to obtain  $V_{(BR) \text{ max}}$ .

An example of a calculated curve compared to one derived from test measurements (Figure 1) illustrates the feasibility and conservative aspects of this method. Surge tests were performed on a 20 piece sample at 25 degrees C with a 10/1000  $\mu$ s waveform.

The curve based on surge test data has a more-shallow slope than the curve interpolated through calculation. This indicates that the devices are conservatively rated and the formula given is adequate for interpolating intermediate values of  $V_C$  for a fractional part of  $I_{pp}$ .

The linear relationship between  $I_p$  and  $V_C$  can be applied in determining greater  $I_{pp}$  ratings for applications requiring lower than normal values of  $V_C$ . In the equation above, insert the desired value for  $V_C$  and solve for the higher  $I_{pp}$  value. This often requires upgrading to a higher peak pulse power ( $P_{pp}$ ) rated device.

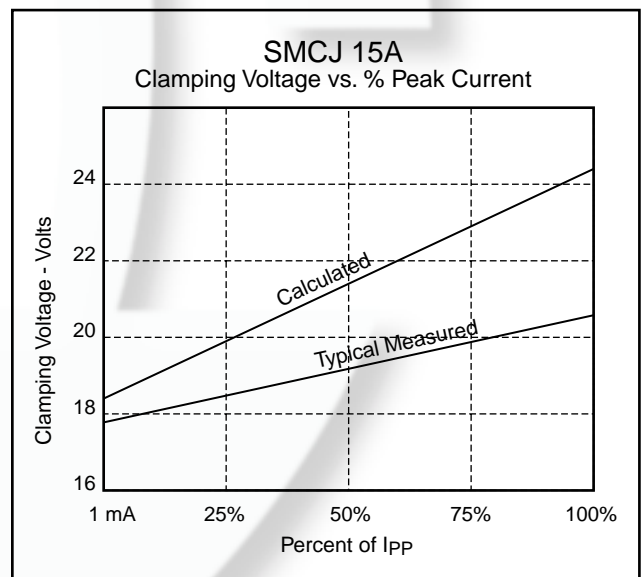


Figure 1

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